

Test Report

No. : CE/2010/C4756 Date : 2011/01/06 Page: 1 of 3

JAZZ SEMICONDUCTOR
4321 JAMBOREE RD., NEWPORT BEACH, CA 92660



The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description : SEMICONDUCTOR WAFERS
Style/Item No. : 0.35 MICRON TECHNOLOGY TOWER SEMICONDUCTOR. 150mm WAFER
Sample Receiving Date : 2010/12/27
Testing Period : 2010/12/27 TO 2011/01/06

Test Requested : To determine the release of Nickel content in the submitted sample with reference to Entry 27 of Regulation (EC) No 552/2009 amending Annex XVII of REACH Regulation (EC) No 1907/2006 (formerly directive 94/271EC)

Test Result(s) : Please refer to next page(s).

Summary :

Sample No.	Result
1	PASS


James Lu / Supervisor
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory – Taipei



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No. : CE/2010/C4756 Date : 2011/01/06 Page: 2 of 3

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Test Result(s)

Sample list/list of materials of Sample

Sample No.	TEST PART DESCRIPTION
1	WAFER

Nickel Release Test

Test Method: With reference to BS EN 1811:1998+A1:2008. Analysis was performed by ICP-AES.

Sample	Sample Area (cm ²)	Volume of Test Solution (ml)	Nickel Release (µg/cm ² /week)	Adjusted Nickel Release (µg/cm ² /week)	Specified Limit (µg/cm ² /week)	Conclusion
1	349.65	350	<0.1	<0.01	0.5	PASS
			<0.1	<0.01		PASS

Note : Conclusions on Pass/Fail are based on the test result from the actual sampling of the received samples(s).

1. < = less than

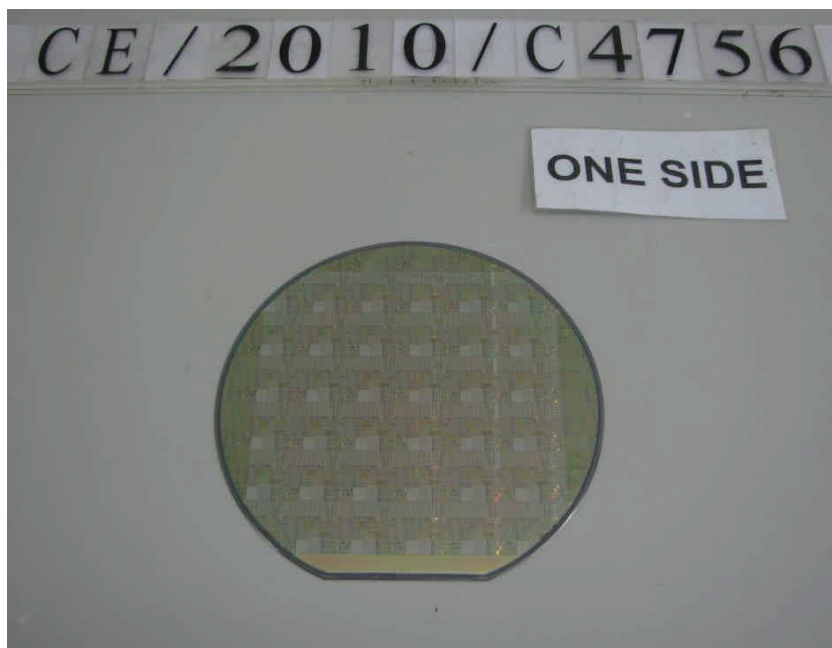
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**** End of Report ****

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